ARFTG

96th ARFTG Microwave Measurement Symposium

Measurement Techniques for Accelerating the Design of 5G Circuits and Systems

Hard Rock Hotel, San Diego, CA, USA, January 17-20, 2021 www.arftg.org

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CALL FOR PAPERS

The theme for the 96th ARFTG Conference (which will be co-located with Radio and Wireless Week) is "Measurement Techniques for Accelerating the Design of 5G Circuits and Systems." We encourage the submission of original papers demonstrating innovative approaches in state-of-the-art high-frequency test and measurement. Contributions exploring all areas of RF, microwave, and mm-wave measurements are welcome. Suggested topics include but are not limited to:

- Nonlinear Measurements, Modeling, and Linearization
- Over-the-Air (OTA) and MIMO Characterization
- On-Wafer Techniques
- Modulated Waveform Measurements
- Techniques for Connector-less Environments
- Traceability in Calibrations and Measurement Uncertainty
- Characterizing Material Properties
- Applications and Advances in Vector Network Analysis

Deadlines

September 25, 2020 Electronic abstract/summary is due in PDF format.

October 23, 2020 Paper acceptance and classification will be communicated.

November 13, 2020 Publication-ready paper is due in PDF format.

Instructions for Authors

Instructions for authors are outlined briefly below. More details can be found on the ARFTG website: http://www.arftg.org/index.php/upcoming-conference/author-instructions. Authors are strongly encouraged to use the template on that webpage to prepare both initial summary and final paper submissions.

We request that authors submit a 4-page summary with supporting figures of both experimental setups and measurement results to enable evaluation with respect to the interests of the participants and the novelty of the work.

Contributed papers will be presented as 20-minute talks or in an interactive poster session. Final papers will be published as part of the ARFTG proceedings in IEEE Xplore, provided it has been presented at the conference.

Financial Support for Students

ARFTG provides financial support to graduate students to attend the fall/winter ARFTG conference with our ARFTG Student Sponsorship Initiative. Please see the program webpage (http://www.arftg.org/index.php/membership/student-sponsorship) or contact our sponsorship chair (Joe Gering, sponsorship@arftg.org) for more details.

Exhibit & Sponsorship

The 96th ARFTG Conference also offers an outstanding exhibition and sponsorship opportunity. Please contact our Exhibits Chair (Joel Dunsmore, exhibits@arftg.org) or our Sponsors Chair (Joe Gering, sponsorship@arftg.org) directly for further information.



